Application/Control No. Applicant(s)/Patent Under Reexamination 10/522,461 JEONG ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Edna Wong 1753 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-5,221,446 06-1993 Eerkens, Jozef W. Α 204/157.22 US-В US-С D US-US-Ε F US-US-G US-Н US-1 US-US-Κ US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY FR 2790974 A1 09-2000 Ν France SCHEIBNER et al. B01D 59/34 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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